# MOSFET - Power, N-Channel, SUPERFET III, Easy Drive 650 V, 30 A, 99 mΩ

# **FCMT099N65S3**

# **Description**

SUPERFET III MOSFET is ON Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advanced technology is tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate. Consequently, SUPERFET III MOSFET is very suitable for the switching power applications such as server / telecom power, adaptor and solar inverter applications.

The Power88 package is an ultra-slim surface-mount package (1 mm high) with a low profile and small footprint (8x8 mm<sup>2</sup>). SUPERFET III MOSFET in a Power88 package offers excellent switching performance due to lower parasitic source inductance and separated power and drive sources. Power88 offers Moisture Sensitivity Level 1 (MSL 1).

### **Features**

- 700 V @  $T_J = 150$ °C
- Typ.  $R_{DS(on)} = 87 \text{ m}\Omega$
- Ultra Low Gate Charge (Typ. Q<sub>g</sub> = 56 nC)
- Low Effective Output Capacitance (Typ. C<sub>oss(eff.)</sub> = 500 pF)
- 100% Avalanche Tested
- These Devices are Pb-Free and are RoHS Compliant

## **Applications**

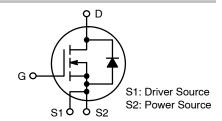
- Telecom / Server Power Supplies
- Industrial Power Supplies
- UPS / Solar



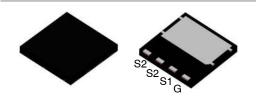
## ON Semiconductor®

### www.onsemi.com

V <sub>DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX	
650 V	99 mΩ @ 10 V	30 A	



**POWER MOSFET** 



PQFN4 8X8 2P CASE 483AP

### **MARKING DIAGRAM**

\$Y&Z&3&K FCMT 099N65S3

\$Y = ON Semiconductor Logo &Z = Assembly Plant Code &3 = Data Code (Year & Week) &K = Lot Code

FCMT099N65S3 = Specific Device Code

### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 2 of this data sheet.

# ABSOLUTE MAXIMUM RATINGS (T<sub>C</sub> = 25°C, Unless otherwise specified)

Symbol	Parameter		Value	Unit
$V_{DSS}$	Drain to Source Voltage		650	V
$V_{GSS}$	Gate to Source Voltage	DC	±30	V
		AC (f > 1 Hz)	±30	V
I <sub>D</sub>	Drain Current	Continuous (T <sub>C</sub> = 25°C)	30	Α
		Continuous (T <sub>C</sub> = 100°C)	19	
I <sub>DM</sub>	Drain Current	Pulsed (Note 1)	75	Α
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		145	mJ
I <sub>AS</sub>	Avalanche Current (Note 1)		4.4	Α
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)		2.27	mJ
dv/dt	MOSFET dv/dt Peak Diode Recovery dv/dt (Note 3)		100	V/ns
			20	
$P_{D}$	Power Dissipation	(T <sub>C</sub> = 25°C)	227	W
		Derate Above 25°C	1.82	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 s		300	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Repetitive rating: pulse-width limited by maximum junction temperature.
- 2.  $I_{AS} = 4.4 \text{ A}$ ,  $R_G = 25 \Omega$ , starting  $T_J = 25^{\circ}\text{C}$ . 3.  $I_{SD} \le 15 \text{ A}$ ,  $di/dt \le 200 \text{ A/}\mu\text{s}$ ,  $V_{DD} \le 400 \text{ V}$ , starting  $T_J = 25^{\circ}\text{C}$ .

### THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{ heta JC}$	Thermal Resistance, Junction to Case, Max.	0.55	°C/W
$R_{ heta JA}$	Thermal Resistance, Junction to Ambient, Max. (Note 4)	45	

<sup>4.</sup> Device on 1 in<sup>2</sup> pad 2 oz copper pad on 1.5 x 1.5 in. board of FR-4 material.

# PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Marking	Package	Reel Size	Tape Width	Shipping <sup>†</sup>
FCMT099N65S3	FCMT099N65S3	PQFN8	13"	13.3 mm	3000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

# **ELECTRICAL CHARACTERISTICS** (T<sub>C</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
OFF CHARACT	ERISTICS	•				
BV <sub>DSS</sub> Dra	Drain to Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}, T_J = 25^{\circ}\text{C}$	650			V
		V <sub>GS</sub> = 0 V, I <sub>D</sub> = 1 mA, T <sub>J</sub> = 150°C	700			V
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 1 mA, Referenced to 25°C		0.68		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 650 V, V <sub>GS</sub> = 0 V			10	μΑ
		V <sub>DS</sub> = 520 V, T <sub>C</sub> = 125°C		2.77		
I <sub>GSS</sub>	Gate to Body Leakage Current	V <sub>GS</sub> = ±30 V, V <sub>DS</sub> = 0 V			±100	nA
ON CHARACTE	RISTICS	•				
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 0.7 \text{ mA}$	2.5		4.5	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 15 A		87	99	mΩ
9FS	Forward Transconductance	V <sub>DS</sub> = 20 V, I <sub>D</sub> = 15 A		17		S
OYNAMIC CHA	RACTERISTICS	•		•		•
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 400 V, V <sub>GS</sub> = 0 V, f = 1 MHz		2270		pF
C <sub>oss</sub>	Output Capacitance			50		pF
C <sub>oss(eff.)</sub>	Effective Output Capacitance	V <sub>DS</sub> = 0 V to 400 V, V <sub>GS</sub> = 0 V		500		pF
C <sub>oss(er.)</sub>	Energy Related Output Capacitance	V <sub>DS</sub> = 0 V to 400 V, V <sub>GS</sub> = 0 V		74		pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10 V	V <sub>DS</sub> = 400 V, I <sub>D</sub> = 15 A, V <sub>GS</sub> = 10 V		56		nC
Q <sub>gs</sub>	Gate to Source Gate Charge	(Note 5)		13		nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge	7		23		nC
ESR	Equivalent Series Resistance	f = 1 MHz		0.5		Ω
WITCHING CH	IARACTERISTICS	•				
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 400 V, I <sub>D</sub> = 15 A,		22		ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, R_g = 4.7 \Omega$ (Note 5)		20		ns
t <sub>d(off)</sub>	Turn-Off Delay Time	7		58		ns
t <sub>f</sub>	Turn-Off Fall Time	7		5		ns
OURCE-DRAI	N DIODE CHARACTERISTICS		-	-	-	-
I <sub>S</sub>	Maximum Continuous Source to Drain Diode Forward Current				30	Α
I <sub>SM</sub>	Maximum Pulsed Source to Drain Diode Forward Current				75	Α
V <sub>SD</sub>	Source to Drain Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 15 A			1.2	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{DD} = 400 \text{ V}, I_{SD} = 15 \text{ A}, dI_{F}/$		352		ns
Q <sub>rr</sub>	Reverse Recovery Charge	dt = 100 A/μs		6.5		μС

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

5. Essentially independent of operating temperature typical characteristics.

### TYPICAL PERFORMANCE CHARACTERISTICS

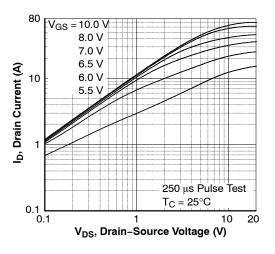


Figure 1. On-Region Characteristics

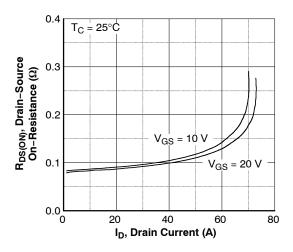


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

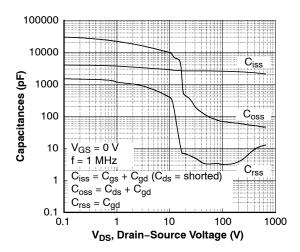


Figure 5. Capacitance Characteristics

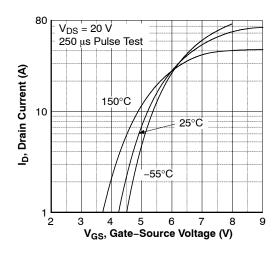


Figure 2. Transfer Characteristics

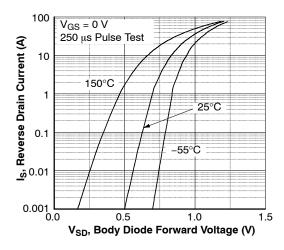


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

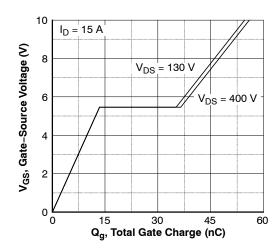


Figure 6. Gate Charge Characteristics

# TYPICAL PERFORMANCE CHARACTERISTICS (Continued)

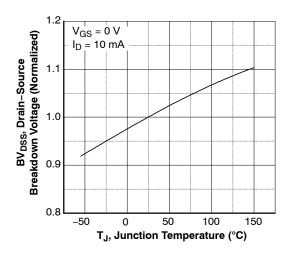


Figure 7. Breakdown Voltage Variation vs. Temperature

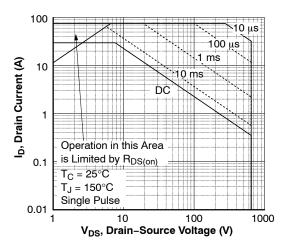


Figure 9. Maximum Safe Operating Area

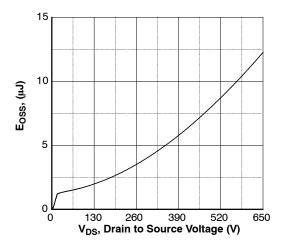


Figure 11.  $E_{\mbox{OSS}}$  vs. Drain to Source Voltage

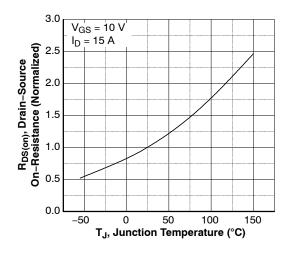


Figure 8. On–Resistance Variation vs. Temperature

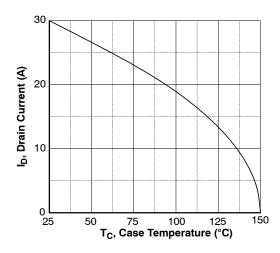


Figure 10. Maximum Drain Current vs. Case Temperature

# TYPICAL PERFORMANCE CHARACTERISTICS (Continued)

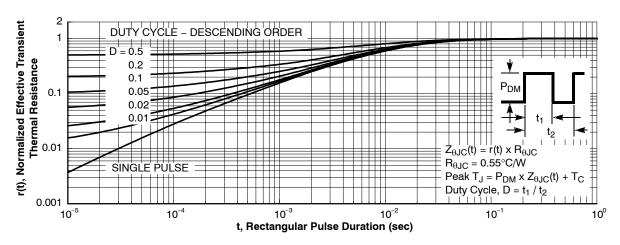


Figure 12. Transient Thermal Response Curve

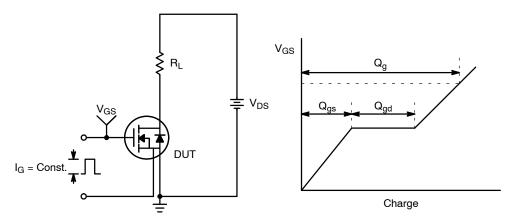


Figure 13. Gate Charge Test Circuit & Waveform

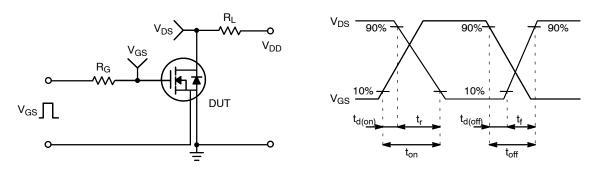


Figure 14. Resistive Switching Test Circuit & Waveforms

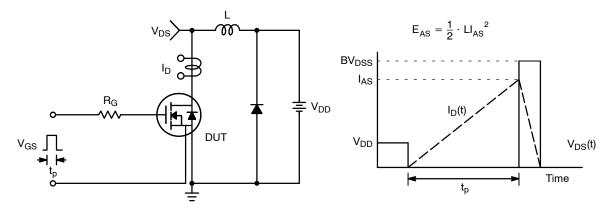


Figure 15. Unclamped Inductive Switching Test Circuit & Waveforms

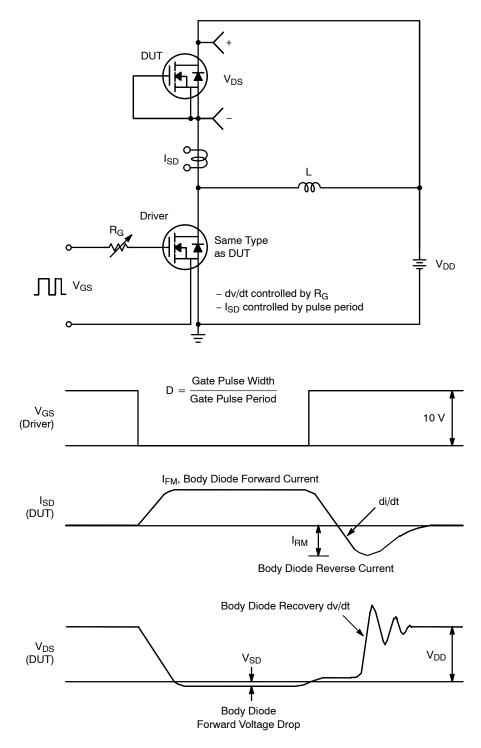


Figure 16. Peak Diode Recovery dv/dt Test Circuit & Waveforms

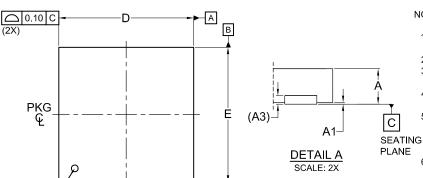
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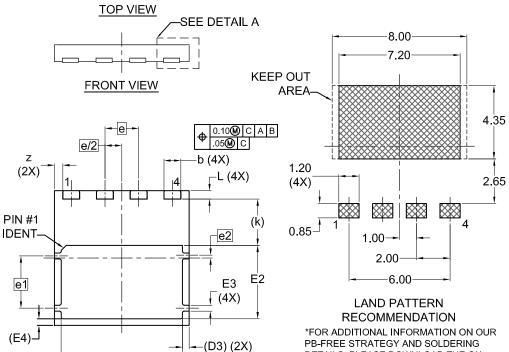
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### NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- 3. COPLANARITY APPLIES TO THE EXPOSED PADS AS WELL AS THE TERMINALS.
- 4. DIMENSIONS D1 AND E1 DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.
- SEATING PLANE IS DEFINED BY THE TERMINALS. "A1" IS DEFINED AS THE DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.
- IT IS RECOMMENDED TO HAVE NO TRACES OR VIAS WITHIN THE KEEP OUT AREA.



DIM	MILLIMETERS				
Diivi	MIN.	NOM.	MAX.		
Α	0.90	1.00	1.10		
A1	0.00	-	0.05		
А3	(	0.20 REF			
b	0.90	1.00	1.10		
D	7.90	8.00	8.10		
D2	7.10	7.30			
D3	0.40 REF				
E	7.90	8.00	8.10		
E2	4.25	4.35	4.45		
E3	0.25	25 0.35 0.			
E4	0.40 REF				
е	2.00 BSC				
e/2	1.00 BSC				
e1	3.10 BSC				
e2	0,17 BSC				
k	2,75 REF				
L	0.40	0.50	0.60		

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